

Specification for

**Harmonized system of
quality assessment for
electronic
components —
Semiconductor discrete
devices —**

Blank detail specification —

**Bidirectional triode thyristors (triacs),
ambient or case-rated up to 100 A**

Amendments issued since publication

Amd. No.	Date	Comments

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National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Policy Committee ECL/-. It is identical with IEC Publication 747-6-2:1991 QC 750111 “*Semiconductor devices — Discrete devices — Part 6: Thyristors. Section 2 — Blank detail specification for bidirectional triode thyristors (triacs), ambient or case-rated, up to 100A*” published by the International Electrotechnical Commission (IEC).

Cross-references The British Standard harmonized with QC 001001 and QC 001002 is BS 9000 “*General requirements for a system for electronic components of assessed quality*”.

International Standard ^a	Corresponding British Standard
IEC 68-2-17:1978	BS 2011 <i>Environmental testing</i> Part 2.1Q:1981 <i>Test Q. Sealing</i> (Identical)
IEC 747-6:1983	BS 6493 <i>Semiconductor devices</i> Part 1: <i>Discrete devices</i> Section 1.6:1984 <i>Recommendations for thyristors</i> (Identical)
IEC 747-10/QC 700000:1984	BS 9970 <i>Harmonized system of quality assessment for electronic components. Semiconductor devices</i> Part 0:1985 <i>Generic specification</i> (Identical)
IEC 747-11/QC 750000:1985	BS QC 750000:1986 <i>Harmonized system of quality assessment for electronic components. Discrete semiconductor devices. Sectional specification</i> (Identical)
IEC 749:1984	BS 6493 <i>Semiconductor devices</i> Part 3:1985 <i>Mechanical and climatic test methods</i> (Identical)

^a Some standards are undated in the text.

There is no corresponding British Standard for IEC 191, but BS 3934 “*Specification for dimensions of semiconductor devices and integrated electronic circuits*” is a related standard.

A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

Summary of pages

This document comprises a front cover, an inside front cover, pages i and ii, pages 1 to 10 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

Introduction

The IEC Quality Assessment System for Electronic Components is operated in conformance with the statutes of the IEC and under the authority of the IEC. The object of this system is to define quality assessment procedures in such a manner that electronic components released by one participating country as conforming with the requirements of an applicable specification are equally acceptable in all other participating countries without the need for further testing.

This blank detail specification is one of a series of blank detail specifications for semiconductor devices and should be used with the following IEC publications:

747-10/QC 700000 (1984): *Semiconductor devices, Part 10: Generic specification for discrete devices and integrated circuits.*

747-11/QC 750000 (1985): *Semiconductor devices, Part 11: Sectional specification for discrete devices.*

Required information

Numbers shown in brackets on this and the following pages correspond to the following items of required information, which should be entered in the spaces provided.

Identification of the detail specification

- [1] The name of the National Standards Organization under whose authority the detail specification is issued.
- [2] The IECQ number of the detail specification.
- [3] The numbers and issue numbers of the generic and sectional specifications.
- [4] The national number of the detail specification, date of issue and any further information required by the national system.

Identification of the component

- [5] Type of component
- [6] Information on typical construction and applications. If a device is designed to satisfy several applications, this should be stated in the detail specification. Characteristics, limits and inspection requirements for these applications shall be met. If a device is electrostatic sensitive, a caution statement should be added in the detail specification.
- [7] Outline drawing and/or reference to the relevant document for outlines.
- [8] Category of assessed quality.
- [9] Reference data on the most important properties to permit comparison between component types.